

## UMF Equipment – Surface Profiler

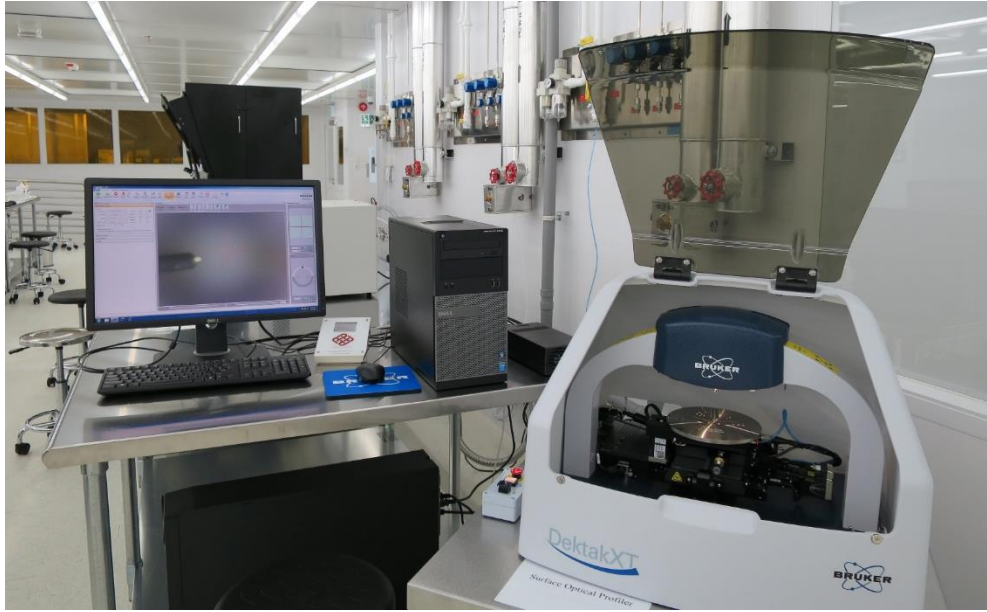
### Bruker DektakXT

A surface profiler is a metrology instrument for topographical characterization of a sample's uppermost layers. Our profiler provides repeatable, accurate measurements on varied surfaces, from traditional 2D roughness surface characterization and step height measurements to advanced 3D mapping.

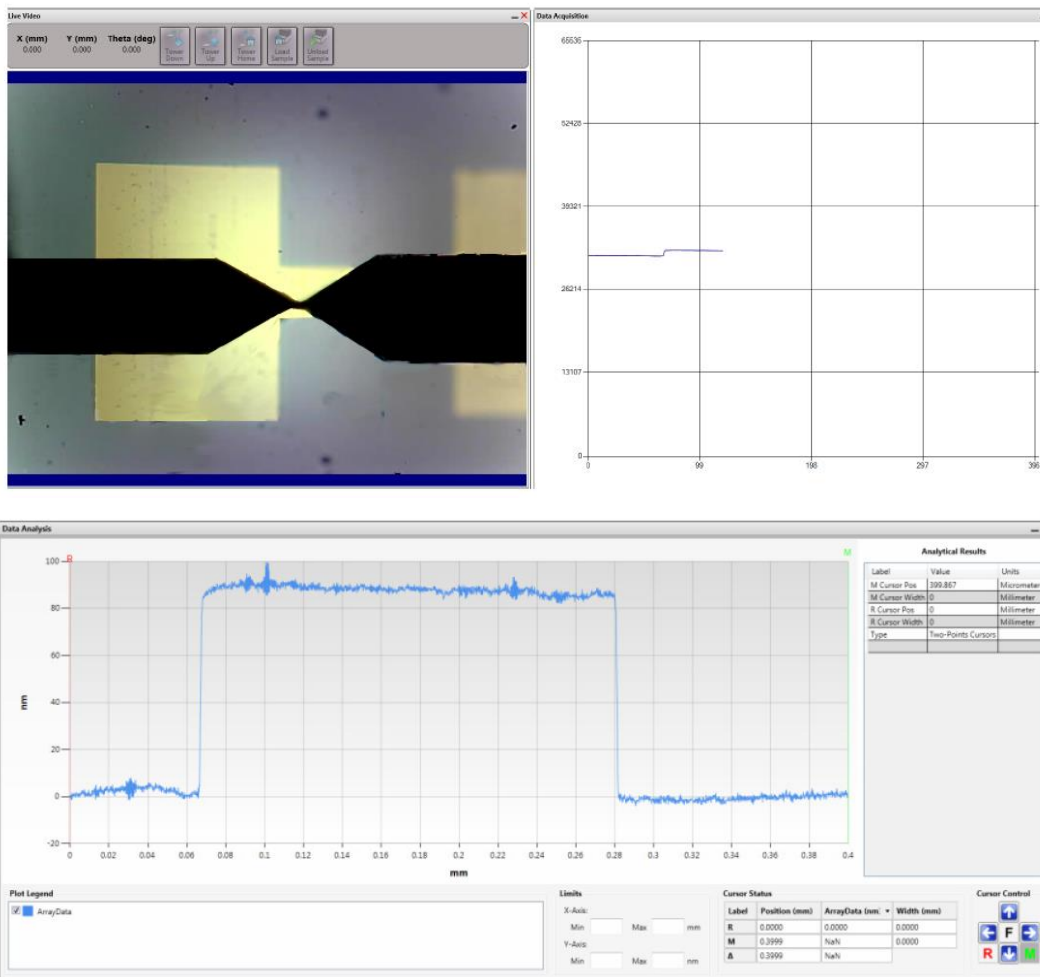
- Features:
- Max. substrate size: Up to 4"
  - Max. sample thickness: 50mm
  - Measurement: Line scan and mapping
  - Stylus: Diamond tip
  - Stylus radius: 2 $\mu$ m
  - Stylus force: 1 – 15mg
  - Data points per scan: 120,000 max.
  - Vertical resolution: max. 1Å (@ 6.55  $\mu$ m range)

Please refer to supplier information page: <https://www.bruker.com/en/products-and-solutions/test-and-measurement/stylus-profilometers.html> for further details of the system.

For any inquiry, please contact Dr. Terence Wong (Tel: 3400 2075; Email: [tai-lun.wong@polyu.edu.hk](mailto:tai-lun.wong@polyu.edu.hk)).



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Top: Real-Time Measurement Trace; Bottom: Output Display for a Single-Scan Measurement